Electronic Supplementary Information (ESI)

XPS – Graphene Oxide Characterisation

We independently acquired XPS chemical analysis of the 'as received' graphene oxide (performed with a VG-Microtech Multilab 3000 electron spectrometer) which reveals the material to comprise of 59 % C1s at 284.6 eV which correspond to graphitic groups, 29 % of C1s at 286.8 eV which is characteristic of C-O bonds and 11.5 % of C1s at 288.2 eV which correspond to C=O bonds.

ESI Figure 1

De-convoluted XPS spectrum of carbon 1s of the commercially available graphene oxide (graphene oxide was utilised as provided by the manufacturer).¹



References:

ESI1. <u>www.graphene-supermarket.com</u>.